

Applicant: Junji Yumoto et al.
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 For: LASER LIGHT SOURCE

Confirmation No.: 8722
 Att'y Docket No.: 14321.69
 Art Unit: 2828

THIRD SUPPLEMENTAL INFORMATION DISCLOSURE
CITATIONS MADE BY APPLICANT

U.S. Patent Documents

| <u>Examiner</u> <u>Initial*</u> | <u>Document</u> <u>Number</u> | <u>Issue</u> <u>Date</u> | <u>Name</u> |
|------------------------------------|----------------------------------|-----------------------------|-------------|
| _____ 1 | 5,767,519 A | 06/16/1998 | Gelbwachs |

Foreign Patent Documents

| <u>Examiner</u> <u>Initial*</u> | <u>Document</u> <u>Number</u> | <u>Publication</u> <u>Date</u> | <u>Country or</u> <u>Patent Office</u> | <u>Translation</u> |
|------------------------------------|----------------------------------|-----------------------------------|---|--------------------|
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Other Documents

(including author, title, pertinent pages, etc.)

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_____ 2 Toshitsugu Ueda et al., *Spectroscopic Detection of Ammonia Using Diode-Pumped Difference-Frequency Generation*, Proceedings of the SPIE - The International Society for Optical engineering SPIE-Int. Soc. Opt. Eng USA, Vol. 4268, 2001, pp. 21-25.

References Cited by Applicants

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The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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